

09891310_CLS
Most Frequently Occurring Classifications of Patents Returned
From A Search of 09891310 on February 10, 2004

Original Classifications

23	714/727
5	714/726
2	324/765
2	714/724
2	714/733
2	716/4

Cross-Reference Classifications

7	714/30
7	714/726
5	714/727
5	714/729
5	714/733
4	714/731
3	326/86
3	714/724
3	714/728
2	324/73.1
2	324/765
2	365/201
2	714/732
2	714/734
2	714/738
2	716/18

Combined Classifications

28	714/727
12	714/726
8	714/30
7	714/733
5	714/724
5	714/729
4	324/765
4	714/728
4	714/731
3	326/86
3	714/734
3	714/738
2	324/158.1
2	324/73.1
2	365/201
2	714/732
2	714/736

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2 716/18
2 716/4

09891310_CLSTITLES

Titles of Most Frequently Occurring Classifications of Patents Returned

From A Search of 09891310 on February 10, 2004

28	714/727	(23 OR, 5 XR)
	Class 714 :	ERROR DETECTION/CORRECTION AND FAULT DETECTION/RECOVERY
	714/699	PULSE OR DATA ERROR HANDLING
	714/724	.Digital logic testing
	714/726	..Scan path testing (e.g., level sensitive scan design (LSSD))
	714/727	...Boundary scan
12	714/726	(5 OR, 7 XR)
	Class 714 :	ERROR DETECTION/CORRECTION AND FAULT DETECTION/RECOVERY
	714/699	PULSE OR DATA ERROR HANDLING
	714/724	.Digital logic testing
	714/726	..Scan path testing (e.g., level sensitive scan design (LSSD))
8	714/30	(1 OR, 7 XR)
	Class 714 :	ERROR DETECTION/CORRECTION AND FAULT DETECTION/RECOVERY
	714/100	DATA PROCESSING SYSTEM ERROR OR FAULT HANDLING
	714/1	.Reliability and availability
	714/25	..Fault locating (i.e., diagnosis or testing)
	714/27	...Particular access structure
	714/30Built-in hardware for diagnosing or testing within-system component (e.g., microprocessor or test mode circuit, scan path)
7	714/733	(2 OR, 5 XR)
	Class 714 :	ERROR DETECTION/CORRECTION AND FAULT DETECTION/RECOVERY
	714/699	PULSE OR DATA ERROR HANDLING
	714/724	.Digital logic testing
	714/733	..Built-in testing circuit (BILBO)
5	714/724	(2 OR, 3 XR)
	Class 714 :	ERROR DETECTION/CORRECTION AND FAULT

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DETECTION/RECOVERY

714/699 PULSE OR DATA ERROR HANDLING
714/724 .Digital logic testing

5 714/729 (0 OR, 5 XR)

Class 714 : ERROR DETECTION/CORRECTION AND FAULT
DETECTION/RECOVERY

714/699 PULSE OR DATA ERROR HANDLING

714/724 .Digital logic testing

714/726 ..Scan path testing (e.g., level sensitive sca

n

design (LSSD))

714/729 ...Plural scan paths

4 324/765 (2 OR, 2 XR)

Class 324 : ELECTRICITY: MEASURING AND TESTING

324/500 FAULT DETECTING IN ELECTRIC CIRCUITS AND OF
ELECTRIC COMPONENTS

324/537 .Of individual circuit component or element

324/765 ..Test of semiconductor device

4 714/728 (1 OR, 3 XR)

Class 714 : ERROR DETECTION/CORRECTION AND FAULT
DETECTION/RECOVERY

714/699 PULSE OR DATA ERROR HANDLING

714/724 .Digital logic testing

714/726 ..Scan path testing (e.g., level sensitive sca

n

design (LSSD))

714/728 ...Random pattern generation (includes
pseudorandom pattern)

4 714/731 (0 OR, 4 XR)

Class 714 : ERROR DETECTION/CORRECTION AND FAULT
DETECTION/RECOVERY

714/699 PULSE OR DATA ERROR HANDLING

714/724 .Digital logic testing

714/726 ..Scan path testing (e.g., level sensitive sca

n

design (LSSD))

714/731 ...Clock or synchronization

3 326/86 (0 OR, 3 XR)

Class 326 : ELECTRONIC DIGITAL LOGIC CIRCUITRY

326/62 INTERFACE (E.G., CURRENT DRIVE, LEVEL SHIFT,
ETC.)

326/82 .Current driving (e.g., fan in/out, off chip
driving, etc.)

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326/83	..Field-effect transistor
326/86	...Bus driving
3 714/734	(1 OR, 2 XR)
Class 714 :	ERROR DETECTION/CORRECTION AND FAULT DETECTION/RECOVERY
714/699	PULSE OR DATA ERROR HANDLING
714/724	.Digital logic testing
714/734	..Structural (in-circuit test)
3 714/738	(1 OR, 2 XR)
Class 714 :	ERROR DETECTION/CORRECTION AND FAULT DETECTION/RECOVERY
714/699	PULSE OR DATA ERROR HANDLING
714/724	.Digital logic testing
714/738	..Including test pattern generator
2 324/158.1	(1 OR, 1 XR)
Class 324 :	ELECTRICITY: MEASURING AND TESTING
324/158.1	MISCELLANEOUS
2 324/73.1	(0 OR, 2 XR)
Class 324 :	ELECTRICITY: MEASURING AND TESTING
324/73.1	PLURAL, AUTOMATICALLY SEQUENTIAL TESTS
2 365/201	(0 OR, 2 XR)
Class 365 :	STATIC INFORMATION STORAGE AND RETRIEVAL
365/189.01	READ/WRITE CIRCUIT
365/201	.Testing
2 714/732	(0 OR, 2 XR)
Class 714 :	ERROR DETECTION/CORRECTION AND FAULT DETECTION/RECOVERY
714/699	PULSE OR DATA ERROR HANDLING
714/724	.Digital logic testing
714/732	..Signature analysis
2 714/736	(1 OR, 1 XR)
Class 714 :	ERROR DETECTION/CORRECTION AND FAULT DETECTION/RECOVERY
714/699	PULSE OR DATA ERROR HANDLING
714/724	.Digital logic testing
714/736	..Device response compared to expected fault-free response
2 716/18	(0 OR, 2 XR)
Class 716 :	DATA PROCESSING: DESIGN AND ANALYSIS OF CIRCUIT OR SEMICONDUCTOR MASK

		09891310_CLSTITLES
	716/1	CIRCUIT DESIGN
	716/18	.Logical circuit synthesizer
2	716/4	(2 OR, 0 XR)
	Class	716 : DATA PROCESSING: DESIGN AND ANALYSIS OF
		CIRCUIT OR SEMICONDUCTOR MASK
	716/1	CIRCUIT DESIGN
	716/4	.Testing or evaluating

09891310_LIST

PLUS Search Results for S/N 09891310, Searched February 10, 2004

The Patent Linguistics Utility System (PLUS) is a USPTO automated search system for U.S. Patents from 1971 to the present. PLUS is a query-by-example search system which produces a list of patents that are most closely related linguistically to the application searched. This search was prepared by the staff of the Scientific and Technical Information Center, SIRA.

6556037
5631912
6163864
5872796
5892778
6122762
6219812
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5598421
5949701
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6314539
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5701309
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5042034
5299136
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6321355
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6353905
6370665
6442092

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5936423
5968195
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5935266
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